

Search Notes

Application/Control No.

10/633,530

Examiner

Shih-wen Hsieh

Applicant(s)/Patent under
Reexamination

SAITO ET AL.

Art Unit

2861

SEARCHED

Class	Subclass	Date	Examiner
347	updated	11/30/2005	<i>mik</i> SWH
417	updated	11/30/2005	<i>hmk</i> SWH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
USPGPUB text search (see attached)		11/30/2005	<i>SWH</i> SWH

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR